

**Search Notes****Application/Control No.**

10/561,622

**Examiner**

Son T. Nguyen

**Applicant(s)/Patent under  
Reexamination**

HASHIMOTO ET AL.

**Art Unit**

3643

**SEARCHED**

Class	Subclass	Date	Examiner
119	59S	11/22/2008	STN
	58.1R		
	58.1SC		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
IPC foreign search	11/22/2008	STN
text search, see printouts	11/22/2008	stn